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**Metallic and other inorganic coatings —  
Review of methods of measurement of  
thickness**

*Revêtements métalliques et autres revêtements inorganiques — Vue  
d'ensemble sur les méthodes de mesurage de l'épaisseur*

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## Foreword

ISO (the International Organization for Standardization) is a worldwide federation of national standards bodies (ISO member bodies). The work of preparing International Standards is normally carried out through ISO technical committees. Each member body interested in a subject for which a technical committee has been established has the right to be represented on that committee. International organizations, governmental and non-governmental, in liaison with ISO, also take part in the work. ISO collaborates closely with the International Electrotechnical Commission (IEC) on all matters of electrotechnical standardization.

International Standards are drafted in accordance with the rules given in the ISO/IEC Directives, Part 2.

The main task of technical committees is to prepare International Standards. Draft International Standards adopted by the technical committees are circulated to the member bodies for voting. Publication as an International Standard requires approval by at least 75 % of the member bodies casting a vote.

Attention is drawn to the possibility that some of the elements of this document may be the subject of patent rights. ISO shall not be held responsible for identifying any or all such patent rights.

ISO 3882 was prepared by Technical Committee ISO/TC 107, *Metallic and other inorganic coatings*, Subcommittee SC 2, *Test methods*.

This third edition cancels and replaces the second edition (ISO 3882:1986), which has been technically revised.

## Introduction

This International Standard summarizes the various methods used for the measurement of coating thickness and describes their working principles. Methods of measuring coating thickness may be either destructive or non-destructive (see Table 1). The information given in Table 2 will assist in the choice of typical instrumental methods suitable for thickness measurements. For all instrumental methods, manufacturers' instructions should be followed.

The thickness ranges covered by the different methods depend on the coating materials, thickness of the coating, substrates and instruments used (see Table 3); e.g., although X-ray spectrometry can be used to measure the thickness of a chromium coating, thicknesses of 20  $\mu\text{m}$  or more cannot be measured with sufficient precision. Similarly, while magnetic methods may be used to measure the thickness of a gold coating over a magnetic steel substrate, many magnetic instruments do not have the sensitivity to measure accurately thicknesses of gold coatings less than 2  $\mu\text{m}$ .

Where a referee method is required the appropriate coating specification should be consulted.

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# Metallic and other inorganic coatings — Review of methods of measurement of thickness

## 1 Scope

This International Standard reviews methods for measuring the thickness of metallic and other inorganic coatings on both metallic and non-metallic substrates (see Tables 1, 2 and 3). It is limited to tests already specified, or to be specified, in International Standards, and excludes certain tests that are used for special applications.

**Table 1 — Methods of measuring coating thickness**

| Non-destructive                                           |                          | Destructive                                                                                     |                       |
|-----------------------------------------------------------|--------------------------|-------------------------------------------------------------------------------------------------|-----------------------|
| Split beam microscope (light section)                     | ISO 2128 <sup>a</sup>    | Microscopical (optical)                                                                         | ISO 1463              |
| Magnetic                                                  | ISO 2178<br>and ISO 2361 | Fizeau multiple-beam interferometry                                                             | ISO 3868 <sup>b</sup> |
| Eddy current                                              | ISO 2360                 | Profilometric (stylus)                                                                          | ISO 4518 <sup>b</sup> |
| X-ray spectrometric                                       | ISO 3497                 | Scanning electron microscope                                                                    | ISO 9220              |
| Beta backscatter                                          | ISO 3543                 | Dissolution methods:<br>Gravimetric strip and weigh method and<br>gravimetric analytical method | ISO 10111             |
|                                                           |                          | Coulometric method                                                                              | ISO 2177              |
| <sup>a</sup> Can be destructive in some applications.     |                          |                                                                                                 |                       |
| <sup>b</sup> Can be non-destructive in some applications. |                          |                                                                                                 |                       |

## 2 Normative references

The following referenced documents are indispensable for the application of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

ISO 1463, *Metallic and oxide coatings — Measurement of coating thickness — Microscopical method*

ISO 2064, *Metallic and other inorganic coatings — Definitions and conventions concerning the measurement of thickness*

ISO 2128, *Anodizing of aluminium and its alloys — Determination of thickness of anodic oxide coatings — Non-destructive measurement by split-beam microscope*

ISO 2177, *Metallic coatings — Measurement of coating thickness — Coulometric method by anodic dissolution*

ISO 2178, *Non-magnetic coatings on magnetic substrates — Measurement of coating thickness — Magnetic method*

ISO 2360, *Non-conductive coatings on non-magnetic basis materials — Measurement of coating thickness — Amplitude-sensitive eddy current method*

ISO 2361, *Electrodeposited nickel coatings on magnetic and non-magnetic substrates — Measurement of coating thickness — Magnetic method*

ISO 3497, *Metallic coatings — Measurement of coating thickness — X-ray spectrometric methods*

ISO 3543, *Metallic and non-metallic coatings — Measurement of thickness — Beta backscatter method*

ISO 3868, *Metallic and other non-organic coatings — Measurement of coating thicknesses — Fizeau-multiple beam interferometry method*

ISO 4518, *Metallic coatings — Measurement of coating thickness — Profilometric method*

ISO 9220, *Metallic coatings — Measurement of coating thickness — Scanning electron microscope method*

ISO 10111, *Metallic and other inorganic coatings — Measurement of mass per unit area — Review of gravimetric and chemical analysis methods*

### 3 Terms and definitions

For the purposes of this document, the terms and definitions given in ISO 2064 apply.

### 4 Non-destructive methods

#### 4.1 Split beam microscope (light section) method, ISO 2128

This equipment, originally designed for the measurement of surface roughness, is used for measuring the thickness of transparent and translucent coatings, in particular, anodic oxide coatings on aluminium. A light beam is projected on to the surface at an angle of 45°. Part of the beam is reflected from the surface of the coating and the rest penetrates the coating and is reflected from the coating/metal substrate interface. The distance that separates the two images observed in the eyepiece of the microscope is proportional to the thickness of the coating and can be measured by means of a vernier screw which controls a calibrated graticule. The method can be used where sufficient light is reflected from the coating/metal substrate interface to give a clear image in the microscope. For transparent or translucent coatings, such as anodic oxide films, this method is non-destructive.

For measuring the thickness of opaque coatings, a small area of the coating is removed and in this application the method is destructive. The step between the surface of the coating and the basis metal produces a deflection of the light beam which gives an absolute measure of the coating thickness.

The method is not suitable for hard anodic coatings or for coatings that are very thin (less than 2 µm thick), very thick (greater than 100 µm thick) or rough. It is not suitable for coatings on heavily shot-blasted surfaces. Other methods such as eddy current (ISO 2360), interference microscope (ISO 3868) and microscopical (ISO 1463) may be applicable for thickness measurement where the split beam microscope method cannot be used.

The method is best suited to small parts because of the ease with which they can be set up on the microscope stage.

The measurement uncertainty of the method is usually less than 10 % of the thickness.

#### 4.2 Magnetic methods, ISO 2178 and ISO 2361

Instruments for these methods measure either the magnetic attraction between a magnet and the basis metal, as influenced by the presence of the coating, or the reluctance of a magnetic flux path passing through the coating and the basis metal.

All instruments using magnetic methods are sensitive to the magnetic condition and properties of the test specimen, surface curvature, surface cleanliness, surface roughness, and thickness of the basis metal and of the coating.



These methods are limited in practice to non-magnetic coatings on a magnetic substrate (see ISO 2178) and to electroplated nickel coatings on a magnetic or non-magnetic substrate (see ISO 2361).

The measurement uncertainty of the method is less than 10 % of the thickness or 1,5  $\mu\text{m}$ , whichever is the greater.

#### 4.3 Eddy current method, ISO 2360

ISO 2360 describes an amplitude method and is based on differences in electrical conductivity between coatings and substrates. The method is used primarily for measuring the thickness of non-conductive coatings on non-magnetic metals and of single layer metal coatings on non-conductors. If this method is used for measuring thicknesses of metallic coatings on metallic substrates, great care is necessary if acceptable results are to be obtained.

The method is ideal for rapid determination of anodic coating thickness measurements on aluminium and its alloys and is well suited for use in field measurements. For autocatalytic nickel coatings, this method gives erratic measurements due to variations in conductivity of the coatings with changes in phosphorous content.

ISO 2360 only covers the measurement of the thickness of a non-conductive coating on a non-magnetic basis metal.

The measurement uncertainty of the method is usually less than 10 % of the thickness or 0,5  $\mu\text{m}$ , whichever is the greater.

#### 4.4 X-ray spectrometric methods, ISO 3497

These methods use emission and absorption X-ray spectrometry for determining the thickness of metallic coatings.

X-rays are made to irradiate a fixed area of the coated surface, and the intensity of the secondary radiation emitted by the coating or by the substrate and attenuated by the coating is measured. A correlation exists between the intensity of the X-rays and the coating thickness; this is established using calibration standards.

This method's accuracy is reduced:

- when constituents of the coating are present in the basis metal, and vice versa;
- when more than two coatings are superimposed;
- when the chemical composition of a coating varies greatly from that of the calibration standard.

The method is not applicable above a certain thickness which depends on the atomic numbers and densities of the materials involved.

For autocatalytic nickel coatings this method is only recommended for deposits in the as-plated condition. The phosphorus content of the coating should be known in order to enable calculation of the thickness of the deposit. As the matrix effect due to the distribution of phosphorus in layers of the coating also affects the measurement uncertainty, the calibration standards have to be made under the same conditions as those of the production process.

Instruments capable of measuring the thickness of a coating with an uncertainty of less than 10 % of the thickness are commercially available.

#### 4.5 Beta backscatter method, ISO 3543

This method uses radio isotopes that emit beta rays and detectors that measure the intensity of those beta rays backscattered by the test specimen. The intensity of the backscattered beta rays will be between two values, namely the backscatter intensity of the coating and that of the basis metal. The measurement is only possible if the atomic number of the coating material is sufficiently different from that of the substrate. The

instrument is calibrated using calibration standards having the same coating and substrates as the specimen to be measured. The measured intensity of the beta rays backscattered by the test specimen is used to calculate the mass per unit area of the coating, which, provided that the test specimen is of uniform density, is directly proportional to the thickness.

This method can be used for both thin and heavy coatings, the maximum thickness being a function of the coating material density.

A measurement uncertainty of less than 10 % of the thickness over a wide range of thickness can be achieved using this method.

## **5 Destructive methods**

### **5.1 Microscopical (optical) method, ISO 1463**

In this method, coating thickness is measured on a magnified image of a cross-section of the coating using an optical microscope.

The measurement uncertainty of this method is less than 10 % of the thickness subject to a minimum error of 0,8  $\mu\text{m}$ . However, with careful preparation of the specimen and the application of suitable instruments this method is capable of providing a measurement uncertainty of 0,4  $\mu\text{m}$  under reproducible conditions.

### **5.2 Fizeau multiple-beam interferometry method, ISO 3868**

By completely dissolving a small area of the coating without attacking the substrate, or by masking an area before plating, a step is formed from the surface of the coating to that of its substrate. The height of this step is measured with a multiple-beam interferometer.

This method is particularly useful for measuring the thickness of very thin opaque metal coatings. It is not suitable for vitreous enamel coatings. This method is essentially a laboratory technique and is useful for measuring the thickness of coatings on standards used for calibrating non-destructive test instruments such as beta backscatter and X-ray spectrometry instruments, especially for standards with rather thin (sub-micron) coatings.

This method provides an absolute measure of the microscopic vertical surface variation ranging from 0,002  $\mu\text{m}$  to 0,2  $\mu\text{m}$ . The measurement uncertainty is  $\pm 0,001 \mu\text{m}$ .

### **5.3 Profilometric (stylus) method, ISO 4518**

By masking during the coating process, or by dissolving a small area of the coating without attacking the substrate, a step is formed from the surface of the substrate to that of the coating. A stylus is drawn across this step and its height is determined by electronically measuring and recording the motion of the stylus.

Available commercial instruments allow measurements to be made over the range 0,01 mm to 0,000 02 mm (20 nm).

The measurement uncertainty of this method is less than 10 % of the thickness.

### **5.4 Scanning electron microscope method, ISO 9220**

In this method, coating thickness is measured on a magnified image of a cross-section of the coating using a scanning electron microscope. The measurement is made on a conventional micrograph or on a photograph of the video waveform signal for a single scan across the coating. Errors can occur if both the calibration and the measurement are not made over the same segment of the field, as the magnification may not be uniform over the entire field. The magnification also often drifts with time introducing further error in the thickness measurement.

The measurement uncertainty is less than 10 % of the thickness or 0,1  $\mu\text{m}$ , whichever is the greater.

## 5.5 Dissolution methods

### 5.5.1 Coulometric method, ISO 2177

The metallic coating thickness is determined by measuring the quantity of electricity consumed in dissolving the coating from a precisely defined area when the article is made anodic in a suitable electrolyte under suitable conditions.

The change in potential that occurs when the underlying material is reached serves to indicate the end-point of the dissolution. The method is applicable to metallic coatings on both metallic and non-metallic substrates.

The measurement uncertainty of the method is less than 10 % of the thickness.

### 5.5.2 Gravimetric (strip and weigh) method, ISO 10111

In this method, the coating mass is determined by weighing the sample before and after dissolving the coating without attacking the substrate, or by weighing the coating after dissolving the substrate without attack of the coating. The coating has to be of uniform density.

The mass of the coating divided by the density and the area of the coating gives the average coating thickness.

The limitation of the method is that it does not indicate the presence of bare spots or sites with thicknesses lower than the specified minimum in the measuring areas. Additionally, the single value obtained from each measuring area is the mean thickness over that area: there can be no further mathematical analysis of this single value, e.g. for statistical process control purposes.

The measurement uncertainty of this method is less than 5 % of the thickness over a wide range of thicknesses.

### 5.5.3 Gravimetric (analytical) method, ISO 10111

In this method, the coating mass is determined by dissolving the coating, with or without dissolving the substrate material, and determining the quantity of coating metal by chemical analysis.

The mass of the coating divided by the density and the area of the coating gives the average coating thickness.

The limitations of the method are as follows:

- it is not reliable if the same metal is present in the coating and in the substrate or in the basis metal;
- it does not indicate the presence of bare spots or sites with thicknesses lower than the specified minimum in the measuring areas;
- the single value obtained from each measuring area is the mean thickness over that area: there can be no further mathematical analysis of this single value, e.g. for statistical process control purposes.

The measurement uncertainty of this method is normally less than 5 % of the thickness over a wide range of thicknesses.

Table 2 — Applicability of typical instrumental methods for coating thickness measurement

| Substrate           | Coating                       |                              |                 |                              |                              |                              |                             |                                |                                                             |                                           |                              |                             |                               |                              |                            |                                                                       |                               |                              |
|---------------------|-------------------------------|------------------------------|-----------------|------------------------------|------------------------------|------------------------------|-----------------------------|--------------------------------|-------------------------------------------------------------|-------------------------------------------|------------------------------|-----------------------------|-------------------------------|------------------------------|----------------------------|-----------------------------------------------------------------------|-------------------------------|------------------------------|
|                     | Al and alloys                 | Ag                           | AO <sup>a</sup> | Au                           | Cd                           | Cr                           | Cu                          | Ni <sup>b</sup>                | Ni <sup>c</sup>                                             | NM <sup>d</sup>                           | Pb                           | Pd                          | Rh                            | Sn                           | Sn-Ni                      | Sn-Pb                                                                 | VE <sup>e</sup>               | Zn                           |
| Al and alloys       | —                             | BCX                          | E               | BCX                          | BCX                          | BCXE                         | BCX                         | BCX <sub>M<sup>f,g</sup></sub> | B <sup>Ch</sup> E <sup>f,h</sup> <sub>X<sup>h,i</sup></sub> | E                                         | BCX                          | BCX                         | B <sup>i</sup> X <sup>j</sup> | BCX                          | BCX                        | B <sup>i</sup> X <sup>j</sup> C <sup>j</sup>                          | E                             | BCX                          |
| Ag                  | B <sup>X<sup>k</sup></sup> C  | —                            | X               | BCX                          | BCX                          | BCX <sub>E</sub>             | BCX                         | BCX <sub>M<sup>f,g</sup></sub> | B <sup>Ch,i</sup> X <sup>E</sup>                            | B <sup>E<sup>i</sup></sup> X <sup>i</sup> | BCX                          | X <sup>i</sup>              | X                             | CX                           | X                          | B <sup>i</sup> X                                                      | E <sup>i</sup>                | BCX                          |
| Cu and alloys       | B <sup>X<sup>k</sup></sup>    | BCX                          | E               | BCX                          | BCX                          | BCXE                         | C <sup>j</sup> X            | CX <sub>M<sup>f,g</sup></sub>  | C <sup>h</sup> E <sup>f</sup> X <sup>i</sup>                | B <sup>E<sup>i</sup></sup> X <sup>i</sup> | BCX                          | BCX                         | BX                            | BCX                          | BCX                        | B <sup>i</sup> X <sup>j</sup> C <sup>j</sup>                          | E <sup>i</sup>                | CX                           |
| Mg and alloys       | B <sup>X<sup>k</sup></sup>    | BX                           | E               | BX                           | BX                           | BX                           | BX                          | BX <sub>M<sup>f,g</sup></sub>  | B <sup>X<sup>h</sup></sup> E <sup>f,h</sup>                 | E                                         | BX                           | BCX                         | BX                            | BX                           | BX                         | B <sup>i</sup> X                                                      | E                             | BX                           |
| Ni                  | BX <sup>M<sup>k</sup></sup>   | BCX <sup>M<sup>k</sup></sup> | B               | BCX <sup>M<sup>k</sup></sup> | BCX <sup>M<sup>k</sup></sup> | BCX <sup>M<sup>k</sup></sup> | CX <sup>M<sup>k</sup></sup> | S                              | —                                                           | M <sup>k</sup> X <sup>i</sup>             | BCX <sub>M<sup>k</sup></sub> | BX <sup>M<sup>k</sup></sup> | BX <sup>M<sup>k</sup></sup>   | BCX <sub>M<sup>k</sup></sub> | X <sup>M<sup>k</sup></sup> | B <sup>i</sup> C <sup>j</sup> X <sub>M<sup>k</sup></sub> <sup>j</sup> | M <sup>k</sup> X <sup>i</sup> | CX <sup>M<sup>k</sup></sup>  |
| Ni-Co-Fe            | BM <sub>X<sup>l,k</sup></sub> | BM CX                        | X               | BCMX                         | BCMX                         | CMX                          | CMX                         | CX <sup>i</sup>                | CX <sup>i</sup> M <sup>f</sup>                              | BM <sup>i</sup> X <sup>i</sup>            | BCMX                         | BMX                         | BMX                           | BM CX                        | X                          | BM <sub>C<sup>j</sup></sub> X <sup>j</sup>                            | X <sup>i</sup> M <sup>i</sup> | MCX                          |
| NM <sup>d</sup>     | BEX                           | BCXE <sup>m</sup>            | —               | BCXE <sup>m</sup>            | BCXE <sup>m</sup>            | BCXE <sup>m</sup>            | BCXE <sup>m</sup>           | BCX <sub>M<sup>f,g</sup></sub> | B <sup>Ch</sup> X <sup>m</sup> <sub>E<sup>f,h</sup></sub>   | —                                         | BCX <sub>E<sup>m</sup></sub> | BXE <sup>m</sup>            | BXE <sup>m</sup>              | BCXE <sub>m</sub>            | X <sup>E<sup>m</sup></sup> | B <sup>i</sup> C <sup>j</sup> X <sub>E<sup>m</sup></sub> <sup>j</sup> | —                             | BCX <sub>E<sup>m</sup></sub> |
| Steels <sup>o</sup> | BM <sup>X<sup>k</sup></sup>   | BCMX                         | X               | BCMX                         | BCMX                         | CMX <sup>h</sup>             | CMX                         | CX <sub>M<sup>f,g</sup></sub>  | C <sup>h</sup> M <sup>X<sup>i</sup></sup>                   | BEM <sup>X<sup>i</sup></sup>              | BCMX                         | BMX                         | BMX                           | BCMX                         | X                          | B <sup>i</sup> M <sub>C<sup>j</sup></sub> X <sup>j</sup>              | M <sup>X<sup>i</sup></sup>    | BCMX                         |
| Steels <sup>p</sup> | B <sup>X<sup>k</sup></sup>    | BCXE <sup>m</sup>            | X               | BCXE <sup>m</sup>            | BCX                          | CX <sup>n</sup>              | CXE <sup>m</sup>            | CX <sub>M<sup>f,g</sup></sub>  | C <sup>h</sup> X <sup>h,i</sup>                             | BEX <sup>i</sup>                          | BCX                          | BCX                         | BX                            | BCX                          | XC                         | B <sup>i</sup> X <sup>j</sup> C <sup>j</sup>                          | E <sup>i</sup>                | BCX                          |
| Ti                  | B <sup>i</sup> X <sup>k</sup> | BCXE <sup>m</sup>            | X               | BCXE <sup>m</sup>            | BCX                          | CX                           | BCXE <sup>m</sup>           | BCX <sub>M<sup>f,g</sup></sub> | B <sup>Ch</sup> X <sup>i</sup>                              | B <sup>E<sup>i</sup></sup> X <sup>i</sup> | BX                           | BCX                         | BCX                           | BCX                          | —                          | B <sup>i</sup> C <sup>j</sup> X                                       | X <sup>i</sup>                | BCX                          |
| Zn and alloys       | B <sup>X<sup>k</sup></sup>    | BCX                          | X               | BX                           | BX                           | CX                           | CX                          | CX <sub>M<sup>f,g</sup></sub>  | CX <sup>h,i</sup>                                           | BEX <sup>i</sup>                          | BX                           | BCX                         | BX                            | BCX                          | —                          | B <sup>i</sup> X                                                      | E <sup>i</sup> X <sup>i</sup> | —                            |